

Search Notes

Application/Control No.

10/705,890

Examiner

Duc M. Nguyen

Applicant(s)/Patent under
Reexamination

OESCH, YVES

Art Unit

2685

SEARCHED

Class	Subclass	Date	Examiner
455	41.1 41.2 41.3		
	42->45		
	567		
	572		
	575.6		
	90.1->		
	->90.3		
	59 106		
	347->349		
379	428.02		
	433.1		
	433.11		
	441 443		
	447	2/15/2006	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/15/2006	DN